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***m*-Plane GaN Growth on “Double Miscut” Bulk Substrates for Blue Laser Diode Applications** LEAH KURITZKY, DANIEL MYERS, KATHRYN KELCHNER, SHUJI NAKAMURA, STEVE DENBAARS, CLAUDE WEISBUCH, JAMES SPECK, Univ of California - Santa Barbara — Although nearly 100% of today’s commercial GaN devices are grown on the *c*-plane, the non-polar *m*-plane is an alternative orientation that is free from polarization-induced electric fields, which separate carrier wavefunctions in *c*-plane InGaN quantum wells (QWs) and reduce radiative recombination rates compared to *m*-plane. Performance of *m*-plane blue laser diodes is currently limited by low In uptake and broad linewidth in the blue spectrum compared to *c*-plane. This work examines the impact of *m*-plane surface miscut on these performance aspects. The morphology was examined by atomic force microscopy for homoepitaxy on co-loaded substrates: on-axis, -1° *c*-miscut, 1° *a*-miscut. All three films showed regions of diagonal *a* + *c* step direction where pure *a*- or *c*-direction steps were expected. These *a* + *c* regions also emitted longer wavelength in fluorescence and cathodoluminescence than other step directions. “Double miscut” substrates in the combined *a*- and *c*-directions take advantage of the observed stable *a* + *c* step direction and redshift. Multi-QWs on double miscut substrates exhibited <30 nm linewidth in the blue spectrum and higher In uptake than ever achieved for standard miscut *m*-plane.

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